

PTO-1449		Application No. 10/649,925		Applicant(s) Kovacevic et al.	
Information Disclosure In an Application		Docket Number 021791.0109		Group Art Unit 2125	Filing Date 08/25/2003

U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
CK A	6,122,564	09/19/2000	Koch et al.	700	123	06/30/1998
CK B	6,188,041	02/13/2001	Kim et al.	219	121.63	11/13/1998
CK C	6,311,099	10/30/2001	Jasper et al.	700	166	10/15/1998
CK D	6,401,001	06/04/2002	Jang et al.	700	118	07/22/1999
CK E	6,459,951	10/01/2002	Griffith L.	700	166	09/10/1999
CK F	6,526,327	02/25/2003	Kar et al.	700	119	12/07/2000
CK G	6,638,787	10/28/2003	Buchin et al.	438	75	12/04/2001
CK H	US 2004/0107019	06/03/2004	Keshavmurthy et al.	700	118	07/18/2003
I						
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K						
L						
M						
N						

FOREIGN PATENT DOCUMENTS

	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
CK O	JP 11174578 A	07/06/1999	Japan	B23K	26/02	XX	
CK P	WO 03/070414 A1	08/28/2003	PCT	B23K	26/03	XX	
Q							

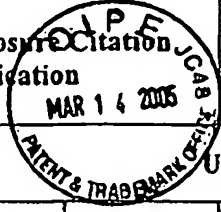
OTHER DOCUMENTS (Including Author, Title, Source, and Pertinent Pages)

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EXAMINER <i>Chunli Kang</i>	DATE CONSIDERED <i>3/28/05</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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PTO-1449		Application No. 10/649,925		Applicant(s) Kovacevic et al. <i>Vak</i>			
Information Disclosure In an Application		Docket Number 021791.0109	Group Art Unit 2125	Filing Date Aug. 25, 2003			
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U.S. PATENT DOCUMENTS							
		DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
CK	A	6,391,251	05/21/02	Keicher et al.	419	7	05/09/2000
CK	B	6,580,959	06/17/2003	Mazumder	700	121	05/19/2000
	C						
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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
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		DOCUMENT (Including Author, Title, Source, and Pertinent Pages)					DATE
CK	E	B. Grünwald et al., "New Technological Developments in Laser Cladding", Proceedings of the International Congress on Applications of Lasers and Electro-Optics (ICALEO 1993), pp. 934-944.					1993
CK	F	Ui et al., "Sensing, Modelling and Closed Loop Control of Powder Feeder for Laser Surface Modification", Proceeding of the International Congress on Applications of Lasers and Electro-Optics (ICLEO 1993), pp. 965-974.					1993
CK	G	F. Merlaudeau et al., "Acquisition and Image Processing System Able to Optimize Laser Cladding Process", From the Proceeding of ICSP '96, Laboratoire GERE - Université de Bourgogne, France, pp. 1628-1631.					1996
CK	H	William H. Hofmeister et al., "Video Monitoring and Control of the Lens Process", Proceedings of AWS 9th International Conference on Computer Technology in Welding, 1998, pp. 187-196					1998
CK	I	Ivan S. Knecko et al., "Influence of Geometrical Factor on Heat Transfer Rate During GTAW for Welding-Based Deposition", Proceedings of Free Symposium on Nontraditional Manufacturing Research and Applications, the 2001 International Mechanical Engineering Conference, Nov. 11-16, 2001., New York, N.Y., (9 pages)					2001
CK	J	D. Hu et al., "Improving Solid Freeform Fabrication by Laser-Based Additive Manufacturing", Research Center for Advanced Manufacturing, Southern Methodist University, Richardson, Texas, USA, © ImechE, 2002, Proc. Instn Mech. Engrs Vol. 216 Part B: J. Engineering Manufacturing, pp. 1253-1264.					2002
CK	K	D Hu et al., "Modelling and Measuring the Thermal Behavior of the Molten Pool in Closed Loop Controlled Laser-Based Additive Manufacturing", Research Center for Advanced Manufacturing, Southern Methodist University, © ImechE, 2003, Proc. Instn Mech. Engrs Vol. 217 Part B: J. Engineering Manufacturing (12 pages)					2003
CK	L	Dongming Hue et al., "Sensing, Modeling and Control for Laser-Based Additive Manufactures", International Journal of Machine Tools & Manufacture 43 (2003) pp. 51-60					2003
	M						
EXAMINER <i>Charlie Koon</i>				DATE CONSIDERED 3/28/05			
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